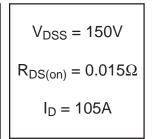
International Rectifier

IRFPS3815PbF

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

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Description

The HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	105	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	74	А
I _{DM}	Pulsed Drain Current ①	390	
P _D @T _C = 25°C	Power Dissipation	441	W
	Linear Derating Factor	2.9	W/°C
V_{GS}	Gate-to-Source Voltage	± 30	V
E _{AS}	Single Pulse Avalanche Energy®	1610	mJ
I _{AR}	Avalanche Current ①	58	A
E _{AR}	Repetitive Avalanche Energy ①	38	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.34	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.24		°C/W
$R_{\theta JA}$	Junction-to-Ambient		40	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	- 0 (, , , , , , , , , , , , , , , , , ,								
	Parameter	Min.	Тур.	Max.	Units	Conditions			
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	150			V	$V_{GS} = 0V, I_D = 250\mu A$			
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.18		V/°C	Reference to 25°C, I _D = 1mA			
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.015	Ω	V _{GS} = 10V, I _D = 63A ④			
V _{GS(th)}	Gate Threshold Voltage	3.0	_	5.0	V	$V_{DS} = 10V, I_D = 250\mu A$			
g _{fs}	Forward Transconductance	47			S	$V_{DS} = 50V, I_D = 58A$			
I _{DSS}	Drain-to-Source Leakage Current			25	μA	V _{DS} = 100V, V _{GS} = 0V			
DSS I	Brain to Godice Leakage Guiterit			250	μΑ	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			
1	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 30V$			
I _{GSS}	Gate-to-Source Reverse Leakage			-100	nA ·	$V_{GS} = -30V$			
Qg	Total Gate Charge		260	390		I _D = 58A			
Q _{gs}	Gate-to-Source Charge		53	80	nC	$V_{DS} = 120V$			
Q _{gd}	Gate-to-Drain ("Miller") Charge		150	230		V _{GS} = 10V4			
t _{d(on)}	Turn-On Delay Time		22			V _{DD} = 75V			
t _r	Rise Time		130			$I_{D} = 58A$			
t _{d(off)}	Turn-Off Delay Time		51		ns	$R_G = 1.03\Omega$			
t _f	Fall Time		60			V _{GS} = 10V ④			
L _D	Internal Drain Inductance		5.0			Between lead,			
	The Hall Plain Haddanee		0.0		nH	6mm (0.25in.)			
	Internal Source Inductance		13			.		''' '	from package
L _S	Internal Source inductance		13			and center of die contact			
C _{iss}	Input Capacitance		6810			$V_{GS} = 0V$			
Coss	Output Capacitance		1570		pF	$V_{DS} = 25V$			
C _{rss}	Reverse Transfer Capacitance		480			f = 1.0MHz, See Fig. 5			
Coss	Output Capacitance		9820			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$			
Coss	Output Capacitance		670			$V_{GS} = 0V$, $V_{DS} = 120V$, $f = 1.0MHz$			
Coss eff.	Effective Output Capacitance ®		1270			$V_{GS} = 0V$, $V_{DS} = 0V$ to 120V			

Source-Drain Ratings and Characteristics

	_	T	I	l					
	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current			105		MOSFET symbol			
	(Body Diode)		105	105 A	showing the				
I _{SM}	Pulsed Source Current		390		200	200	200		integral reverse
	(Body Diode) ①			390		p-n junction diode.			
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 58A$, $V_{GS} = 0V$ ④			
t _{rr}	Reverse Recovery Time		270	410	ns	$T_J = 25^{\circ}C, I_F = 58A$			
Q _{rr}	Reverse RecoveryCharge	T	2990	4490	nC	di/dt = 100A/µs ④			
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)							

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25$ °C, L = 0.96mH $R_G = 25\Omega$, $I_{AS} = 58$ A. (See Figure 12)
- $\label{eq:loss} \begin{array}{l} \mbox{ } 3 \mbox{ } I_{SD} \leq 58A, \mbox{ } di/dt \leq 450A/\mu s, \mbox{ } V_{DD} \leq V_{(BR)DSS}, \\ \mbox{ } T_{J} \leq 175^{\circ} \mbox{C} \end{array}$
- $\ ^{\circ}$ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}

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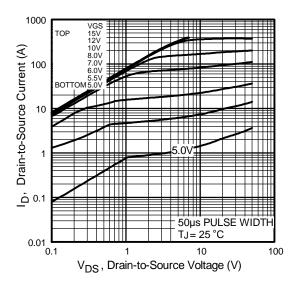


Fig 1. Typical Output Characteristics

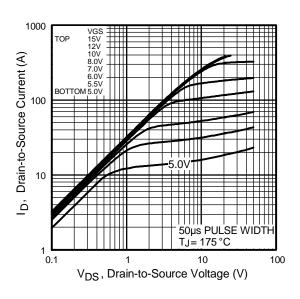


Fig 2. Typical Output Characteristics

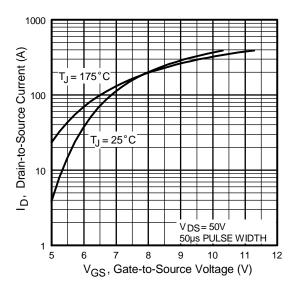


Fig 3. Typical Transfer Characteristics

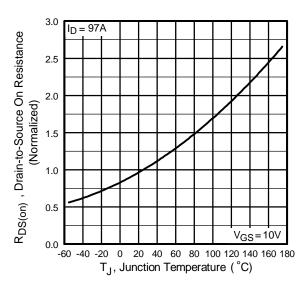


Fig 4. Normalized On-Resistance Vs. Temperature

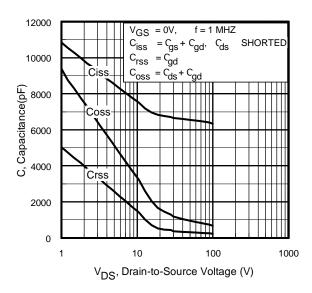


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

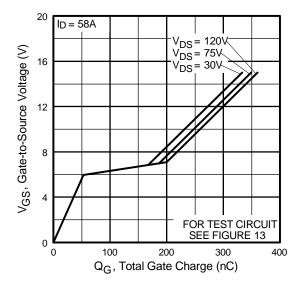


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

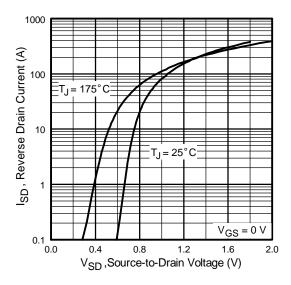


Fig 7. Typical Source-Drain Diode Forward Voltage

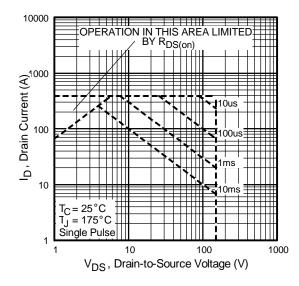


Fig 8. Maximum Safe Operating Area

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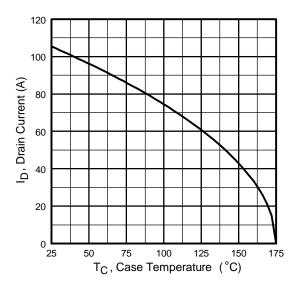
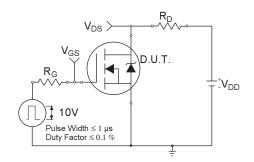
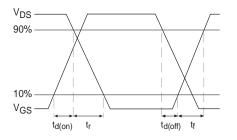


Fig 9. Maximum Drain Current Vs. Case Temperature





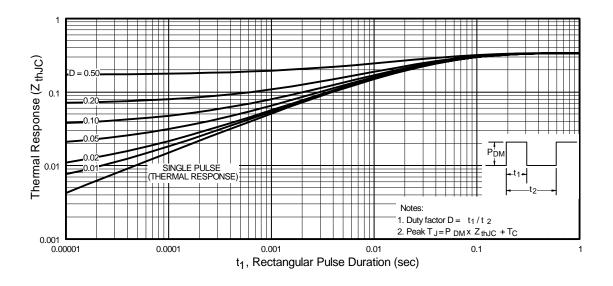


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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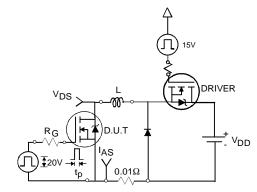


Fig 12a. Unclamped Inductive Test Circuit

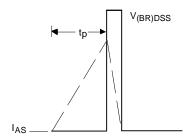


Fig 12b. Unclamped Inductive Waveforms

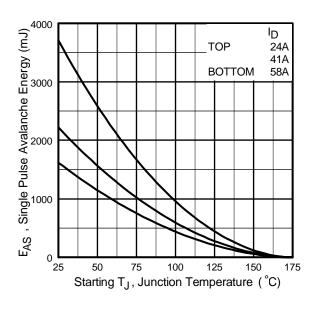


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

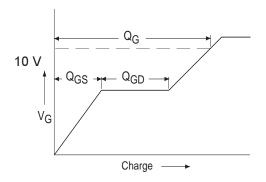


Fig 13a. Basic Gate Charge Waveform

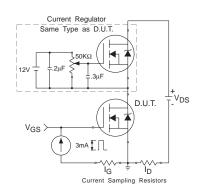
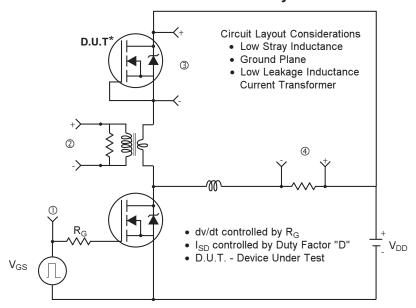


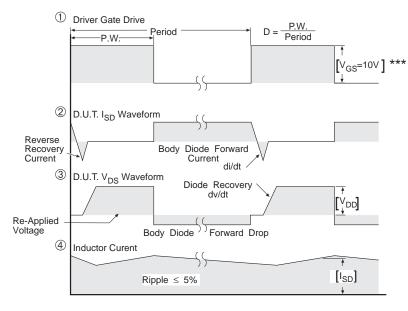
Fig 13b. Gate Charge Test Circuit

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Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel



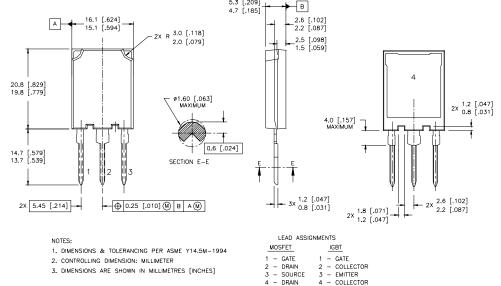
*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

International

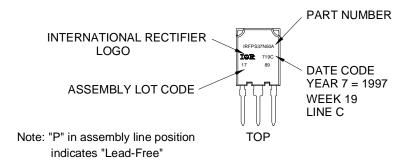
TOR Rectifier

Case Outline and Dimensions — Super-247



Super-247 (TO-274AA) Part Marking Information

EXAMPLE: THIS IS AN IRFPS37N50A WITH ASSEMBLY LOT CODE 1789 ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"



Data and specifications subject to change without notice. This product has been designed and qualified for the industrial market.

Qualification Standards can be found on IR's Web site.



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